

### MOS FIELD EFFECT TRANSISTOR $\mu$ PA1870

### N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

### **DESCRIPTION**

The  $\mu$ PA1870 is a switching device which can be driven directly by a 2.5-V power source.

The  $\mu$ PA1870 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

### **FEATURES**

- Can be driven by a 2.5-V power source
- · Low on-state resistance

RDS(on)1 =  $20.0 \text{ m}\Omega$  MAX. (VGS = 4.5 V, ID = 3.0 A)

 $R_{DS(on)2} = 21.0 \text{ m}\Omega$  MAX. (Vgs = 4.0 V, ID = 3.0 A)

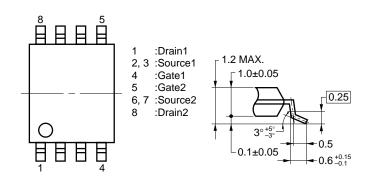
 $R_{DS(on)3} = 27.0 \text{ m}\Omega$  MAX. (Vgs = 2.5 V, ID = 3.0 A)

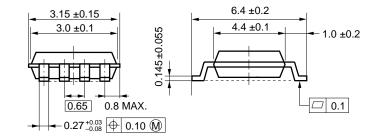
· Built-in G-S protection diode against ESD

### ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1870GR-9JG	Power TSSOP8

### PACKAGE DRAWING (Unit: mm)

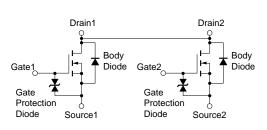




### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	VDSS	20	V
Gate to Source Voltage	Vgss	±12	V
Drain Current (DC)	I <sub>D(DC)</sub>	±6.0	Α
Drain Current (pulse) Note 1	ID(pulse)	±80	Α
Total Power Dissipation Note 2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

### **EQUIVALENT CIRCUIT**



**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1%

2. Mounted on ceramic substrate of 50 cm<sup>2</sup> x 1.1 mm

**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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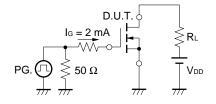
### **ELECTRICAL CHARACTERISTICS (TA = 25°C)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	μΑ
Gate Leakage Current	Igss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.5	1.0	1.5	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 3.0 A	5			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 4.5 V, ID = 3.0 A	12.0	15.0	20.0	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 3.0 A	13.0	15.5	21.0	mΩ
	RDS(on)3	V <sub>G</sub> S = 2.5 V, I <sub>D</sub> = 3.0 A	15.0	20.8	27.0	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V		900		pF
Output Capacitance	Coss	V <sub>G</sub> S = 0 V		295		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		170		pF
Turn-on Delay Time	<b>t</b> d(on)	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 3.0 A		55		ns
Rise Time	tr	V <sub>GS(on)</sub> = 4.0 V		210		ns
Turn-off Delay Time	<b>t</b> d(off)	$R_G = 10 \Omega$		300		ns
Fall Time	tf			340		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 16 V		10		nC
Gate to Source Charge	Qgs	Vgs = 4.0 V		2		nC
Gate to Drain Charge	Q <sub>GD</sub>	ID = 6.0 A		6		nC
Body Diode Forward Voltage	V <sub>F</sub> (S-D)	IF = 6.0 A, VGS = 0 V		0.80		V
Reverse Recovery Time	trr	IF = 6.0 A, VGS = 0 V		400		ns
Reverse Recovery Charge	Qrr	di/dt = 50 A/μs		1000		nC

### **TEST CIRCUIT 1 SWITCHING TIME**

## PG. $\begin{array}{c} D.U.T. \\ \hline \\ RG \\ \hline \\ VDD \\ \hline \\ VDS \\ \hline \\ Wave Form \\ \hline \\ 0 \\ \hline \\ 10\% \\ \hline \\ VDS \\ \hline \\ Wave Form \\ \hline \\ 0 \\ \hline \\ 10\% \\ \hline \\ VDS \\ \hline \\ VDS \\ \hline \\ Wave Form \\ \hline \\ 0 \\ \hline \\ 10\% \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ \hline \\ VDS \\ VDS \\ VDS \\ \hline \\ VDS \\ V$

### **TEST CIRCUIT 2 GATE CHARGE**



90%

90%

10%

VGS(on)

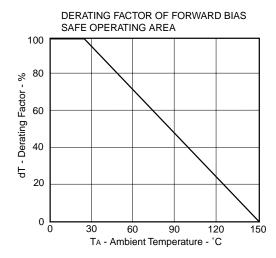
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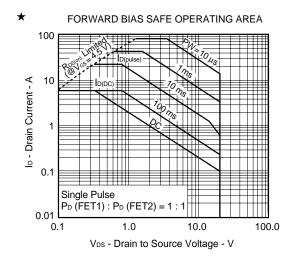
90%

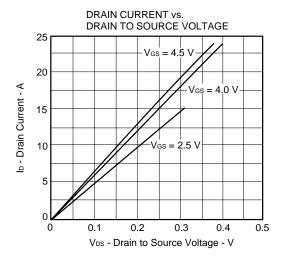
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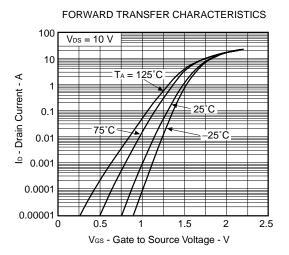


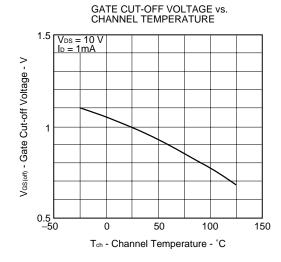
### TYPICAL CHARACTERISTICS (TA = 25°C)

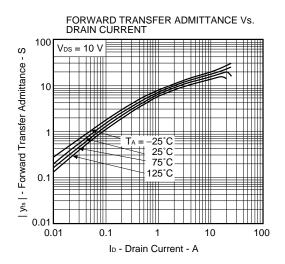






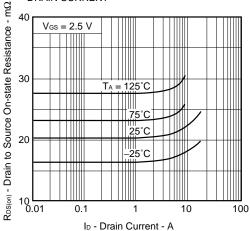




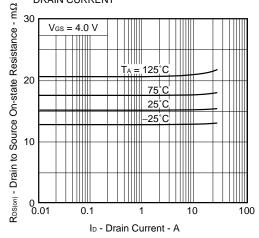


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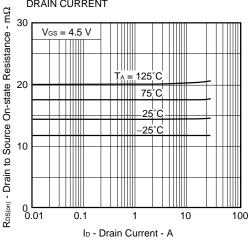
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT** 



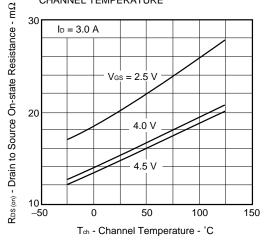
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT** 



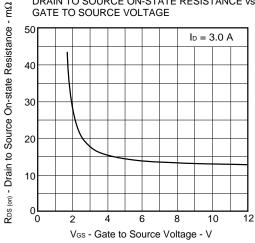
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT** 

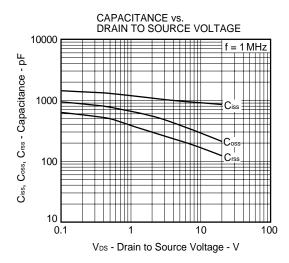


DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



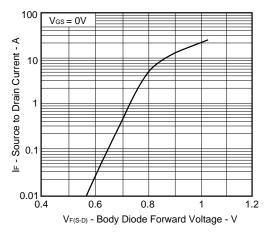
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



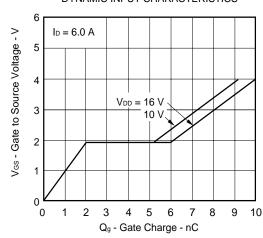


# SWITCHING CHARACTERISTICS 1000 Su Ld(off) tr tr VDD = 10 V VGS(on) = 4 V RG = 10 $\Omega$ ID - Drain Current - A

### SOURCE TO DRAIN DIODE FORWARD VOLTAGE



### DYNAMIC INPUT CHARACTERISTICS



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